

2010 Proceedings of the 56th IEEE Holm Conference on Electrical Contacts

(HOLM 2010)

**Charleston, South Carolina, USA
4 – 7 October 2010**



**IEEE Catalog Number: CFP10HLM-PRT
ISBN: 978-1-4244-8174-3**

TABLE OF CONTENTS

Foreword	xix
The 2010 Ragnar HOLM Scientific Achievement Award.....	xx
Morton Antler Lecture.....	xli
Erle Shobert Prize Paper	xlii
The Armington Recognition Award.....	xliv

Fundamentals

Chair: B. Williamson

Co-Chair: R. Martens

1.1	Interpretation of Low DC Current Measurements of a Transformer's Winding Resistance and the Effect of the Tapchanger's Contacts.....	1
	Paul G. Slade, Consultant, United States	
1.2	Contribution of Nanotechnologies on the Study of the Physical Phenomena of the Arc Birth	11
	B. De Fonseca, LICB, France	
	J. Rossignol, LICB, France	
	E. Bourillot, LICB, France	
	P. Teste, LGEP, France	
1.3	Voltage Fluctuation of Short-Time Arc at Slowly Separating Silver-Based Contacts	18
	Yoshiki Kayano, Akita University, Japan	
	Kazuaki Miyanaaga, Akita University, Japan	
	Hiroshi Inoue, Akita University, Japan	
1.4	Cathode Root Motion Studies of High Current Arcs Using an Optical Fiber Array Based Imaging System	24
	J. W. McBride, University of Southampton, United Kingdom	
	K. J. Cross, United Kingdom	

Connector Design / Modelling

Chair: B. Malucci

Co-Chair: G. Flowers

2.1	A Multi-Physics Finite Element Analysis of Round Pin High Power Connectors	30
	J. Robert Polchow, Auburn University, United States	
	S. V. Angadi, Auburn University, United States	
	Robert L. Jackson, Auburn University, United States	
	Song-yul Choe, Auburn University, United States	
	George T. Flowers, Auburn University, United States	
	Bong-Yi Lee, LS Cable Ltd., Korea	
	Liang Zhong, LS Cable Ltd., Korea	

2.2	Computational Modeling of Electrical Contact Crimping and Mechanical Strength Analysis	39
	Katia Mocellin, CEMEF - Mines ParisTech, France	
	Matthieu Petitprez, CEMEF - Mines ParisTech, France	
	Pierre-Olivier Bouchard, CEMEF - Mines ParisTech, France	
	Christophe Desjean, AIRBUS, France	
2.3	Modeling and Analysis of a Blade/Receptacle Pair for the Prediction of Thermal Cycling and Temperature Dependent Vibration Driven Fretting Corrosion.....	42
	Rebecca D. Ibrahim, Auburn University, United States	
	Chen Chen, Auburn University, United States	
	George T. Flowers, Auburn University, United States	

Materials / Surface Finish I

Chair: J. Zhang

Co-Chair: Z.K. Chen

3.1	Comparison of Hard Au versus Hard Au Flashed PdNi as a Contact Finish	49
	Marjorie Myers, Tyco Electronics, United States	
3.2	Time Dependence Investigation of the Electrical Resistance of Au / Au Thin Film Micro Contacts.....	58
	Pierre-Yves Duvivier, CEA, LETI, MINATEC, France	
	Vincent Mandrillon, CEA, LETI, MINATEC, France	
	Karim Inal, Centre de Microélectronique de Provence / École Nationale Supérieure des Mines de Saint-Étienne, France	
	Christel Dieppedale, CEA, LETI, MINATEC, France	
	Sophie Deldon-Martoscia, CEA, LETI, MINATEC, France	
	Jean-Philippe Polizzi, CEA, LETI, MINATEC, France	
3.3	Analysis of Contact Resistance Behavior for Electric Contacts with Plating Layer	65
	Shigeru Sawada, Mie University, Japan	
	Kaori Shimizu, AutoNetworks, Ltd., Japan	
	Yasuhiro Hattori, AutoNetworks, Ltd., Japan	
	Terutaka Tamai, Mie University, Japan	
	Kazuo Iida, Mie University, Japan	
3.4	A Reliability Study of a New Nanocrystalline Nickel Alloy Barrier Layer for Electrical Contacts.....	73
	Trent K. Do, Amphenol, United States	
	Alan Lund, Xtalic, United States	

Arc Interruption I /Mag. Blow

Chair: G. Witter

Co-Chair: G. Horn

4.1	Study of Arc Mobility and Reignition in a Static Gap Discharge with Magnetic Field	82
	Chi H. Leung, Metalor Electrotechnics, United States	
	Doug Harman, Metalor Electrotechnics, United States	
	Laurent Doublet, Metalor Electrotechnics, France	
	Christine Bourda, Metalor Electrotechnics, France	

4.2	Rotational Drive of Arc Discharges by a Permanent Magnet Embedded in an Electrical Contact Mounted on a Relay	90
	Junya Sekikawa, Shizuoka University, Japan Norimitsu Ban, Shizuoka University, Japan Takayoshi Kubono, Shizuoka University, Japan	
4.3	Magnetic Blowing of Break Arcs up to 360 VDC	96
	A. Vassa, CNRS-UJF, France E. Carvou, University of Rennes 1, France S. Rivoirard, CNRS-UJF, France L. Doublet, Metalor Technologies (France) SAS, France C. Bourda, Metalor Technologies (France) SAS, France D. Jeannot, Metalor Technologies (France) SAS, France P. Ramoni, Metalor Technologies SA, Switzerland N. Ben Jemaa, University of Rennes 1, France D. Givord, CNRS-UJF, France	
Fretting		
Chair: J. McBride		
Co-Chair: G. Flowers		
5.1	Minimum Fretting Amplitude in Medium Force for Connector Coated Material and Pure Metals.....	101
	A. Bouzera, FCI, France E. Carvou, University of Rennes1, France N. Ben Jemaa, University of Rennes1, France R. El Abdi, University of Rennes1, France L. Tristani, FCI, France E. M. Zindine, FCI, France	
5.2	The Influence of Particulate Contaminants on Vibration-Induced Fretting Degradation in Electrical Connectors.....	108
	Jinchun Gao, Beijing University of Posts and Telecommunications, China Chen Chen, Auburn University, United States George T. Flowers, Auburn University, United States Robert L. Jackson, Auburn University, United States Michael J. Bozack, Auburn University, United States	
5.3	Experimental Study of the Vibration-Induced Fretting of Silver-Plated High Power Automotive Connectors	113
	Rujian Fu, Auburn University, United States Song-Yul Choe, Auburn University, United States Robert L. Jackson, Auburn University, United States George T. Flowers, Auburn University, United States Michael J. Bozack, Auburn University, United States Liang Zhong, LS Cable Company, Ltd., Korea, Republic of Daegee Kim, LS Cable Company, Ltd., Korea, Republic of	

Materials / Arcing Contact I

Chair: P. Slade

Co-Chair: H. Czajkowski

- 6.1 A Study of Dynamic Welding of Electrical Contacts with Emphasis on the Effects of Oxide Content for Silver Tin Indium Oxide Contacts 121**
Z. K. Chen, Chugai USA LLC, United States
G. J. Witter, Chugai USA LLC, United States
- 6.2 Basic Investigations on the Behavior of Advanced Ag/SnO₂ Materials for Contactor Applications..... 127**
A. Krätzschmar, Siemens AG, Germany
R. Herbst, Siemens AG, Germany
T. Mützel, Umicore AG & Co. KG, Germany
R. Niederreuther, Umicore AG & Co. KG, Germany
P. Braumann, Umicore AG & Co. KG, Germany
- 6.3 Evaluation of Basic Electrical Parameters of Silver-Based Contact Materials of Different Chemical Composition and Manufacturing Technology 134**
E. Walczuk, Technical University of Lodz, Poland
P. Borkowski, Technical University of Lodz, Poland
S. Ksiezarek, Institute of Non-Ferrous Metals of Gliwice, Poland
W. Missol, Institute of Non-Ferrous Metals of Gliwice, Poland
Z. Rdzawski, Institute of Non-Ferrous Metals of Gliwice, Poland
K. Durst, Institute of Non-Ferrous Metals of Gliwice, Poland
- 6.4 Development of Contact Material Solutions for Low-Voltage Circuit Breaker Applications 142**
Timo Mützel, Umicore AG & Co. KG, Germany
Peter Braumann, Umicore AG & Co. KG, Germany
Ralf Niederreuther, Umicore AG & Co. KG, Germany

Poster Session I: Materials & Arcing Contacts

Chair: G. Horn

Co-Chair: G. Haupt

- P.1 Temperature Measurement of Copper Contact Surfaces..... 148**
R. Landfried, LGEP Institut Carnot C3S, France
T. Leblanc, LGEP Institut Carnot C3S, France
R. Andlauer, France
T. Klonowski, France
Ph. Teste, LGEP Institut Carnot C3S, France
- P.2 The Contribution of Heat Conduction to Bridge Length and Diameter 153**
Kazuaki Miyanaga, Akita University, Japan
Yoshiki Kayano, Akita University, Japan
Tasuku Takagi, Professor Emeritus at Tohoku University, Japan
Hiroshi Inoue, Akita University, Japan

P.3	Two Melting Phenomena in Breaking Ag Contacts Decided by Energizing Electric Circuit.....	158
	Noboru Wakatsuki, Ishinomaki Senshu University, Japan Masahiro Oikawa, Ishinomaki Senshu University, Japan Takayuki Kudo, Ishinomaki Senshu University, Japan Nobuo Takatsu, Ishinomaki Senshu University, Japan	
P.4	Preparation and Study on Performance for Silver Rare-Earth Alloy Electrical Contact Materials	163
	Yancai Zhu, Hebei University of Technology, China Jingqin Wang, Hebei University of Technology, China	
P.5	Electrical Properties of Ag-C Contact Materials Containing Different Allotropes of Carbon	167
	P. Borkowski, Technical University of Lodz, Poland E. Walczuk, Technical University of Lodz, Poland D. Wojcik-Grzybek, Institute of Electronic Materials Technology of Warsaw, Poland K. Frydman, Institute of Electronic Materials Technology of Warsaw, Poland D. Zasada, Military University of Technology of Warsaw, Poland	
P.6	Evaluation of the X-Ray CT Visualisation Technique for Characterising Electrical Contacts	176
	A. V. Lalechos, University of Southampton, United Kingdom J. Swinger, University of Southampton, United Kingdom J. W. McBride, University of Southampton, United Kingdom	
P.7	Calibrated AC and DC Arcing Fault Generator	182
	Jonathan Andrea, LIEN, France Patrick Schweitzer, France Etienne Tisserand, France Patrice Roth, France Serge Weber, France	

Arc Fault / Safety

Chair: B. Miedzinski

Co-Chair: C. Leung

7.1	RF Currents Produced from AC Arcs with Asymmetrical Electrodes.....	188
	John J. Shea, Eaton Corporation, United States Xin Zhou, Eaton Corporation, United States	
7.2	A Study of Arcing Fault in the Low-Voltage Electrical Installation.....	199
	J.-M. Martel, Siemens I BT LV, Germany M. Anheuser, Siemens I BT LV, Germany F. Berger, TU Ilmenau, Germany	
7.3	A New DC and AC Arc Fault Electrical Model.....	210
	Jonathan Andrea, LIEN, France Patrick Schweitzer, LIEN, France Etienne Tisserand, LIEN, France	
7.4	Arc Faults in Photovoltaic Systems.....	216
	Christian Strobl, E-T-A Elektrotechnische Apparate GmbH, Germany Peter Meckler, E-T-A Elektrotechnische Apparate GmbH, Germany	

7.5	Characteristics of Series and Parallel Low Current Arc Faults in the Time and Frequency Domain	223
	Peter Müller, Universität Stuttgart, Germany	
	Stefan Tenbohlen, Universität Stuttgart, Germany	
	Reinhard Maier, Siemens AG, Germany	
	Michael Anheuser, Siemens AG, Germany	

Connector Design/ Modelling

Chair: M. Runde

Co-Chair: D. Gagnon

8.1	Comparison of Model Predictions of Current Density Variation across Simulated Contact Regions.....	230
	Robert D. Malucci, Consultant, United States	
8.2	Observation of Current Flow Point in Contact Surface of a Current Collecting Mechanism	239
	Hiroki Ryobuchi, Nippon Institute of Technology, Japan	
	Noboru Morita, Nippon Institute of Technology, Japan	
	Koichiro Sawa, Nippon Institute of Technology, Japan	
	Takahiro Ueno, Nippon Institute of Technology, Japan	
8.3	Wear Modeling of a Collection of Current Carrying Cantilevered Fibers Sliding against a Plane Moving Surface in a Three Dimensional Magnetic Field	245
	G. S. Erwin, NSWCCD, United States	
	W. A. Lynch, Raven, United States	
	N. A. Sondergaard, BMT Syntek Technologies, United States	

Arc Interruption II

Chair: W. Johler

Co-Chair: J. Shea

9.1	Failure of Arcing Contacts in Low Voltage Switching Devices —Examples, Root Causes, Counter Measures	254
	Volker Behrens, AMI DODUCO GmbH, Germany	
	Thomas Honig, AMI DODUCO GmbH, Germany	
	Oliver Lutz, AMI DODUCO GmbH, Germany	
	Wolfgang Schmitt, AMI DODUCO GmbH, Germany	
	Dietmar Späth, AMI DODUCO GmbH, Germany	
	Brigitte Wörle, AMI DODUCO GmbH, Germany	
9.2	Arc Characteristics and Electrode Mass Change of AgNi Contacts for Electromagnetic Contactors	261
	Koichiro Sawa, Nippon Institute of Technology, Japan	
	Kiyoshi Yoshida, Nippon Institute of Technology, Japan	
	Masaaki Watanabe, Fuji Electric FA Components & Systems Co., Ltd, Japan	
	Kenji Suzuki, Fuji Electric FA Components & Systems Co., Ltd, Japan	
9.3	Experiment Research on High Frequency Making and Breaking Characteristics of Automobile Horn Contacts.....	267
	Jifeng Guo, Harbin Inst. of Tech., China	
	Wanbin Ren, Harbin Inst. of Tech., China	
	Guofu Zhai, Harbin Inst. of Tech., China	
	Hongwei Zhao, Harbin Inst. of Tech. Goodtime Electronics Co. Ltd., China	

9.4	Comparison of the Material Transfer on Corresponding Electrodes in Consideration of the Relative Position and Movement of the Electrical Contacts.....	273
	Martin Weis, Austrian Center of Competence for Tribology, AC ² T research GmbH, Austria	
	Georg Vorlaufer, Austrian Center of Competence for Tribology, AC ² T research GmbH, Austria	
	Frank Berger, TU Ilmenau, Germany	

Materials / Surface Finish II

Chair: E. Smith

Co-Chair: M. Myers

10.1	Characterization Techniques for Nanostructured Contact Materials.....	282
	M. Braunovic, MB Interface Inc., Canada	
10.2	Deposition of Ti-Si-C-Ag Nanocomposite Coatings as Electrical Contact Material.....	288
	Jonas Lauridsen, Linköping University, Sweden	
	Jun Lu, Linköping University, Sweden	
	Per Eklund, Linköping University, Sweden	
	Lars Hultman, Linköping University, Sweden	
	Åke Öberg, ABB, Sweden	
	Mats Lindgren, SP Technical Research of Sweden, Sweden	
	Lars Fast, SP Technical Research of Sweden, Sweden	
	Erik Lewin, Uppsala University, Sweden	
	Ulf Jansson, Uppsala University, Sweden	
10.3	Property of Tin Oxide Film Formed on Tin-Plated Connector Contacts.....	295
	Terutaka Tamaï, Mie University, Japan	
	Yuya Nabeta, Mie University, Japan	
	Shigeru Sawada, Mie University, Japan	
	Yasuhiro Hattori, AutoNetworks Technologies, Ltd., Japan	
10.4	Three-Dimensional Structural Transition of Tin Plated Fretting Contacts.....	303
	Tetsuya Ito, AutoNetworks Technologies, Ltd., Japan	
	Shigeru Ogihara, AutoNetworks Technologies, Ltd., Japan	
	Yasuhiro Hattori, AutoNetworks Technologies, Ltd., Japan	

Materials/Arcing Contact II

Chair: H. Inoue

Co-Chair: D. Moore

11.1	Microswitch Lifecycle Test Fixture for Simultaneously Measuring Contact Resistance (R_c) and Contact Force (F_c) in Controlled Ambient Environment.....	309
	Thomas A. Edelman, United States	
	Ronald A. Coutu Jr., Air Force Institute of Technology, United States	
11.2	Contact Resistance Characteristics of Relay Operated in the Vicinity of Silicone-Type and Non-Silicone-Type Polymeric Cured Materials at Elevated Temperatures.....	317
	Makoto Hasegawa, Chitose Inst. of Science & Technology, Japan	
	Yoshiyuki Kohno, Kaneka Corporation, Japan	

11.3	Influence of Contact Resistance in Carbon-Gold Contacts in Automotive Keypad Switches	323
	J. Praquin, Renault, France	
	C. Gautherot, Renault, France	
	J. Rivenc, Renault, France	
	N. Ben Jemaa, University of Rennes 1, Japan	
	R. El Abdi, University of Rennes 1, Japan	
	J. B. Mitchell, University of Rennes 1, Japan	
	E. Carvou, University of Rennes 1, Japan	

Modelling / Contact Resistance & Thermal

Chair: R. Timsit

Co-Chair: R. Jackson

12.1	An Experimental Study to Determine Electrical Contact Resistance.....	329
	Christophe Pradille, CEMEF - Mines ParisTech, France	
	Francois Bay, CEMEF - Mines ParisTech, France	
	Katia Mocellin, CEMEF - Mines ParisTech, France	
12.2	Automatic Construction of a Computational Model for a Three-Dimensional Resistance Network.....	334
	Keiji Mashimo, Furukawa Electric, Japan	
	Yukihiro Saita, Furukawa Electric, Japan	
	Yasuyuki Ishimaru, FITEC, Japan	
12.3	A Study of Degradation Phenomenon of Electrical Contacts by Hammering Oscillating Mechanism: Data and Modeling	340
	Shin-ichi Wada, Japan	
	Koichiro Sawa, Japan	

MEMS / Nanocontact

Chair: T. Schoepf

Co-Chair: R. Coutu

13.1	Contact Resistance in Flat-on-Flat and Sphere-on-Flat Thin Films	348
	M. B. Read, Massachusetts Institute of Technology, United States	
	J. H. Lang, Massachusetts Institute of Technology, United States	
	A. H. Slocum, Massachusetts Institute of Technology, United States	
	R. Martens, FormFactor, Inc., United States	
13.2	Contact Conductance Quantization in a MEMS Switch.....	356
	Christophe Poulain, CEA-LETI-MINATEC, France	
	Guillaume Jourdan, CEA-LETI-MINATEC, France	
	Alexis Peschot, CEA-LETI-MINATEC, France	
	Vincent Mandrillon, CEA-LETI-MINATEC, France	

13.3	Multi-Physical Characterization of Micro-Contact Materials for MEMS Switches	363
	A. Broue, NOVA MEMS, France J. Dhennin, NOVA MEMS, France P.-L. Charvet, CEA-LETI, France P. Pons, LAAS CNRS, France N. Ben Jemaa, IPR- Université de Rennes, France P. Heeb, NTB, Switzerland F. Coccetti, NOVA MEMS, France R. Plana, LAAS CNRS, France	
13.4	Impact of Creep and Softening Mechanisms on the Contact Resistance of RF MEMS Ohmic Switches: Study of the Current and Time Effects on Au-to-Au Microcontacts in Static Contact Conditions	373
	Frédéric Souchon, CEA-LETI-MINATEC, France Alexis Peschot, CEA-LETI-MINATEC, France Pierre Louis Charvet, CEA-LETI-MINATEC, France Christophe Poulain, CEA-LETI-MINATEC, France	
13.5	Electrical Conduction Properties of Molecular Ultrathin Layers in a Nanocontact	380
	S. Noël, Supelec, France D. Alamarguy, Supelec, France F. Hauquier, Supelec, France F. Houzé, Supelec, France P. Viel, CEA, France S. Palacin, CEA, France	
Poster Session II: Materials / Surface Finish; Sliding; Modelling		
Chair: B. Rickett		
Co-Chair: R. Jackson		
P.8	The Design of a Fretting Contact Resistance Testing System	387
	Na Lu, Beijing University of Posts and Telecommunications, China L. J. Xu, Beijing University of Posts and Telecommunications, China J. Y. Lin, Peking University, China	
P.9	A Multi-Physics Finite Element Model of a 35A Automotive Connector Including Multiscale Rough Surface Contact	392
	Santosh V. Angadi, Auburn University, United States Robert L. Jackson, Auburn University, United States Song-yul Choe, Auburn University, United States George T. Flowers, Auburn University, United States Bong-Yi Lee, LS Cable Ltd., Korea, Republic of Liang Zhong, LS Cable Ltd., Korea, Republic of	
P.10	Large Magnetic Apparatus for Sliding Electric Contact Investigations	403
	D. Maribo, NSWCCD, United States M. Gavrilash, NSWCCD, United States P. J. Reilly, NSWCCD, United States W. A. Lynch, Raven, United States N. A. Sondergaard, BMT Syntek Technologies, United States	

P.11	Oxidation-Induced Growth of Sn Whiskers in a Pure Oxygen Gas Environment.....	412
	E. R. Crandall, Auburn University, United States G. T. Flowers, Auburn University, United States R. N. Dean, Auburn University, United States M. J. Bozack, Auburn University, United States	
P.12	Low-Speed Sliding Test of Cu-Ni-Sn Based Composite Materials Containing WS₂.....	417
	Yoshitada Watanabe, Kogakuin University, Japan	
P.13	Experimental Research on Current-Carrying and Friction Characteristics of Sliding Electrical Contact.....	424
	Fengyi Guo, Liaoning Technical University, China Wei Jia, Liaoning Technical University, China Zhonghua Chen, Liaoning Technical University, China Zhiyong Wang, Liaoning Technical University, China Fei Yin, Liaoning Technical University, China Yitao Liu, Huludao Power Supply Company, China Yiming Xue, Beijing Jiaotong University, China	
Connectors		
Chair: P. Dijk		
Co-Chair: B. Rickett		
14.1	Use of Electrical Contact Fundamentals in the Aluminium Smelting Industry – A Case Study.....	430
	D. Molenaar, CSIRO, Australia	
14.2	High Current Testing for Land Grid Array Sockets	439
	Brian Beaman, IBM, United States	
14.3	Joint Resistance of Bolted Copper - Copper Busbar Joints Depending on Joint Force at Temperatures beyond 105 °C.....	444
	S. Schlegel, TU Dresden, Germany S. Großmann, TU Dresden, Germany H. Löbl, TU Dresden, Germany M. Hoidis, ABB Schweiz AG, Switzerland U. Kaltenborn, AREVA Energietechnik GmbH, Germany T. Magier, Siemens AG, Germany	
14.4	The Effects of Surface Finish Roughness on Intermetallic Layer Growth, Intermetallic Interface Roughness, and Solder Joint Reliability.....	452
	C. L. Rodekahr, Presbyterian College, United States M. J. Bozack, Auburn University, United States G. T. Flowers, Auburn University, United States J. C. Suhling, Auburn University, United States D. A. Rodekahr, Auburn University, United States	

Sliding Contacts

Chair: K. Sawa

Co-Chair: S. Cole

- 15.1 Comparison of Several Liquid Metal Sliding Electric Contacts 457**
D. Maribo, NSWCDD, United States
M. Gavrilash, NSWCDD, United States
P. J. Reilly, NSWCDD, United States
W. A. Lynch, Raven, United States
N. A. Sondergaard, BMT Syntek, United States
- 15.2 A Study for Heavily Saturated V-I Characteristics at Carbon Brush / Steel Collector Ring Sliding Contact, on the View Point of Parallel Connected Brush Current Sharing Unbalance..... 464**
Noboru Morita, Nippon Institute of Technology, Japan
Takahiro Ueno, Nippon Institute of Technology, Japan
Makoto Takanezawa, Nippon Institute of Technology, Japan
Toru Otaka, Toshiba Corporation, Japan
Daisuke Hiramatsu, Japan
- 15.3 Carbon Brush and Flat Commutator Wear of DC Motor Driving Automotive Fuel Pump in Various Fuels 471**
Hidenori Tanaka, Nippon Institute of Technology, Japan
Noboru Morita, Nippon Institute of Technology, Japan
Koichiro Sawa, Nippon Institute of Technology, Japan
Takahiro Ueno, Nippon Institute of Technology, Japan

Materials/Arcing Contact III

Chair: F. Berger

Co-Chair: G. Haupt

- 16.1 Mechanical and Material Properties of Metal Matrix Composite Conducting Alloys..... 478**
Lloyd Brown, US Naval Academy, United States
Peter Joyce, US Naval Academy, United States
Andrea Lazzaro, US Naval Academy, United States
- 16.2 Microstructural Changes of Vacuum Interrupter Contact Materials Caused by Switching Operations..... 484**
Reinhard A. Simon, ABB Switzerland Ltd, Switzerland
Jörg F. Löffler, ETH Zurich, Switzerland
Thierry Delachaux, ABB Switzerland Ltd, Switzerland
Dietmar Gentsch, ABB AG, Germany
- 16.3 Arc Behaviour and Material Deterioration of Silver Based Composites Used for Electrical Contacts.... 494**
M. Ommer, Research Institute Precious Metals & Metals Chemistry, Germany
U. E. Klotz, Research Institute Precious Metals & Metals Chemistry, Germany
D. González, Technische Universität Chemnitz, Germany
F. Berger, Technische Universität Chemnitz, Germany
B. Wielage, Technische Universität Chemnitz, Germany

16.4	Simulation of the Current Density Distribution within Electrical Contacts	505
	M. Leidner, Tyco Electronics AMP GmbH, Germany	
	H. Schmidt, Tyco Electronics AMP GmbH, Germany	
	M. Myers, Tyco Electronics US, United States	

Materials / Surface Finish III

Chair: T. Tamai

Co-Chair: B. Rickett

17.1	Growth of Sn Whiskers on Semiconductor and Insulator Surfaces	514
	E. R. Crandall, Auburn University, United States	
	G. T. Flowers, Auburn University, United States	
	R. N. Dean, Auburn University, United States	
	M. J. Bozack, Auburn University, United States	

17.2	Electrical Contact Behavior of Several Typical Materials in Dust at Static and Dynamic Conditions	520
	Yilin Zhou, Beijing University of Posts and Telecommunications, China	
	Yang Lv, Beijing University of Posts and Telecommunications, China	
	Hao Wang, Beijing University of Posts and Telecommunications, China	
	Aili Ma, Beijing University of Posts and Telecommunications, China	
	Hongda Liu, Beijing University of Posts and Telecommunications, China	

17.3	Simulation of the Corrosion Caused by Water Soluble Salt in Dust	532
	Xue-Yan Lin, Research Lab of Electrical contact, BUPT, China	

Fretting & Sliding

Chair: G. Flowers

Co-Chair: G. Drew

18.1	Long-Term Behaviour of Plug-in Connectors with Copper Beryllium Contact Lamellas Depending on Stress Relaxation.....	537
	Nils Lücke, TU Dresden, Germany	
	Steffen Großmann, TU Dresden, Germany	
	Helmut Löbl, TU Dresden, Germany	
	Tom Ledermann, Multi-Contact AG, Switzerland	
	George Freudiger, Multi-Contact AG, Switzerland	

18.2	Sliding Electrical Contacts: Wear and Electrical Performance of Noble Metal Contacts.....	543
	C. Holzapfel, Schleifring und Apparatebau GmbH, Germany	
	P. Heinbuch, Schleifring und Apparatebau GmbH, Germany	
	S. Holl, Schleifring und Apparatebau GmbH, Germany	

18.3	Interconnection Reliability Assessment for Electronic Equipment Exposed to Chlorine Dioxide Used for Biological Decontamination	551
	C. Xu, Alcatel-Lucent, United States	
	D. Fleming, Alcatel-Lucent, United States	
	M. L. Mandich, Alcatel-Lucent, United States	
	W. D. Reents, Alcatel-Lucent, United States	
	G. E. Derkits, Alcatel-Lucent, United States	
	J. P. Franey, Alcatel-Lucent, United States	
	R. Kopf, Alcatel-Lucent, United States	
	S. Ryan, U.S. Environmental Protection Agency National Homeland Security Research Center, United States	
 Arc Interruption III / Modelling		
Chair: B. Jemaa		
Co-Chair: X. Zhou		
 19.1	 Electromigration in a Liquid Bridge before Contact Break.....	 564
	R. S. Timsit, Timron Scientific Consulting Inc., Canada	
 19.2	 3D Finite Element Analysis of the Glass Encapsulated Magnetic Reed Switches under Pyroshock Environment	 570
	Mihai Vladimirescu, COM DEV Ltd, Canada	
	Andre Zybura, COM DEV Ltd, Canada	
	Regina Kwiatkowski, COM DEV Ltd, Canada	
 19.3	 Advanced Arc Model for Computation of Low Current Arc Characteristics	 578
	Peter Zeller, University of Applied Sciences Wels, Austria	
	Thomas J. Schoepf, United States	
 Author Index		 follows page 585